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- ☐ 1. Leakage current reduction in CMOS VLSI circuits by input vector control
Abdollahi, A.; Fallah, F.; Pedram, M.;
[Very Large Scale Integration \(VLSI\) Systems. IEEE Transactions on](#)
Volume 12, Issue 2, Feb. 2004 Page(s):140 - 154
Digital Object Identifier 10.1109/TVLSI.2003.821546
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(560 KB) [IEEE JNL](#)
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- ☐ 2. Leakage current reduction in sequential circuits by modifying the scan chains
Abdollahi, A.; Fallah, F.; Pedram, M.;
[Quality Electronic Design. 2003. Proceedings. Fourth International Symposium on](#)
24-26 March 2003 Page(s):49 - 54
Digital Object Identifier 10.1109/ISQED.2003.1194708
[AbstractPlus](#) | Full Text: [PDF](#)(243 KB) [IEEE CNF](#)
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- ☐ 3. A novel scan chain diagnostics technique based on light emission from leakage current
Song, P.; Stellari, F.; Xia, T.; Weger, A.J.;
[Test Conference. 2004. Proceedings. ITC 2004. International](#)
2004 Page(s):140 - 147
Digital Object Identifier 10.1109/TEST.2004.1386946
[AbstractPlus](#) | Full Text: [PDF](#)(830 KB) [IEEE CNF](#)
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- ☐ 4. A practical built-in current sensor for I_{DDQ} testing
Hoki Kim; Walker, D.M.H.; Colby, D.;
[Test Conference. 2001. Proceedings. International](#)
30 Oct.-1 Nov. 2001 Page(s):405 - 414
Digital Object Identifier 10.1109/TEST.2001.966657
[AbstractPlus](#) | Full Text: [PDF](#)(954 KB) [IEEE CNF](#)
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Kraft, E.; Fischer, P.; Karagounis, M.; Koch, M.; Kruger, H.; Peric, I.; Wermes, N.; Herrmann, C.; Ni M.; Rutten, W.;
[Nuclear Science Symposium Conference Record. 2005 IEEE](#)
Volume 5, 23-29 Oct. 2005 Page(s):2761 - 2765